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PATENT APPLICATION
Docket No.: 8750-017
Client Ref. No.: SPX200110-0010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Sang-Eun LEE and Jae-Sung HAN

Serial No.: 10/068,152 Examiner: Hollington, Jermele M.

Filed: February 6, 2002 Group Art Unit: 2829

Confirmation No.: 7500

For: METHOD OF IDENTIFYING AND ANALYZING
SEMICONDUCTOR CHIP DEFECTS

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER ALLOWANCE UNDER 37 CFR § 312

Responsive to the Notice of Allowance dated March 24, 2005, please amend the application as follows.

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 4 of this paper.

*O.K. to
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11/17/05*